



**Note  
to CIML Members, OIML Corresponding Members  
and Secretariats of OIML TCs/SCs**

**Subject: TC/SC Secretariat Training – Second Session – 2009**

Dear Colleagues,

In April 2008, the Bureau organized a four-day Seminar for the Secretariats of certain OIML Technical Committees and Subcommittees and for experts responsible for the Working Groups established within these Committees and Subcommittees.

On the occasion of the 43rd CIML Meeting in Sydney, the CIML instructed the Bureau to extend this training to those Secretariats which did not participate in the first session, and afterwards to organize updates as necessary.

Consequently, the Bureau is pleased to inform you that a second four-day initial Seminar will be held from 5 to 8 May 2009 at the “Ecole des Mines” in Douai which is located in the North of France (the same venue as for the 2008 session). Following the success of the 2008 event, the Ecole des Mines has again been chosen for its low cost, practical amenities and – as was the case for the 2008 session – all the costs will be borne by the BIML, including travel expenses.

The training program will be slightly revised in line with the comments made by the participants in the 2008 session. A detailed program will be made available at a later date.

We would like to remind you that the objective of the Seminar is to provide TC/SC Secretariats with appropriate knowledge on the following issues:

- the OIML and its aims;
- the current organization of OIML TCs/SCs and their operating rules (procedures for OIML technical work);
- the responsibilities of TC/SC Secretariats (including cooperation with liaison organizations);
- existing general technical documents and OIML Guides (including how to use them when drafting OIML Recommendations), e.g.:
  - OIML D 11 *General requirements for electronic measuring instruments*,
  - OIML D 31 *General requirements for software controlled measuring instruments*,
  - OIML D 29 *Guide for the application of ISO/IEC Guide 65 to assessment of measuring instrument certification bodies in legal metrology*,
  - OIML D 30 *Guide for the application of ISO/IEC 17025 to the assessment of Testing Laboratories involved in legal metrology*, and
  - the draft Guide on uncertainties under development by TC 3/SC 5;
- presentation of the future TC/SC operating rules (currently under development); and
- use of the existing templates, experimental interactive TC/SC WorkGroups and other tools available on the OIML web site.

A presentation of the training materials developed on OIML activities and technical work as indicated above will also be included.

Experts who are responsible for the Secretariats of OIML Technical Committees and Subcommittees and conveners of Working Groups and who did not participate in the first session are invited to send their application for participation to me ([regine.gaucher@oiml.org](mailto:regine.gaucher@oiml.org)) at the BIML **at the latest by 1 February 2009**. To this end, they will directly receive an application form to be filled in.

Please do not hesitate to contact us if you require any additional information.

Yours faithfully,

A handwritten signature in black ink, appearing to read 'R. Gaucher', with a long horizontal flourish extending to the right.

Régine Gaucher  
Project Leader, BIML